

Search Notes

Application/Control No.

10/524,587

Examiner

Pablo N. Tran

Applicant(s)/Patent under
Reexamination

SERNA ET AL

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
370	320		
	428		
	312		
	329		
	3A1		
	349		
	310		
	347		
	348		
	382		
	427		
	395.82		
	392		
	331		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

Search Notes (continued)


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SEARCHED

Class	Subclass	Date	Examiner
370	432		
	400		
	252		
	256		
489	802-803		
	486.1		
	486.3		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR